

## **Resistor-Programmable Temperature Switch and Analog Temperature Sensor**

### **General Description**

The LM57 is a precision, dual-output, temperature switch with integrated analog temperature sensor. The trip temperature  $(T_{TRIP})$  is programmable by using two external 1% resistors. Using extremely small packaged resistors (0.5 mm x 1 mm), the LM57 can be programmed to any of 256 trip temperatures while consuming very little board space. The  $V_{\text{TEMP}}$  output delivers an analog output voltage which is inversely proportional to the measured temperature.

Built-in temperature hysteresis (T<sub>HYST</sub>) keeps the output stable in an environment of thermal oscillation. The digital temperature switch outputs will go active when the die temperature exceeds  $T_{\text{TRIP}}$  and will release when the temperature falls below a temperature equal to T<sub>TRIP</sub> minus T<sub>HYST</sub>. One of the digital outputs, T<sub>OVER</sub>, is active-high with a push-pull structure. The other digital output,  $\overline{T_{OVER}}$ , is active-low with an opendrain structure.

Driving the TRIP-TEST input high will make the digital outputs active. A processor can read the logic level of the temperature switch outputs, confirming that they changed to their active state. This allows for in-situ verification that the comparator and output circuitry are functional after system assembly. When the TRIP-TEST pin is high, the trip-level reference voltage appears at the Vtemp pin. The system could then use this voltage to calibrate the sensor for even tighter accuracy. Tying TOVER to TRIP-TEST will latch the output after it trips. It can be cleared by forcing TRIP-TEST low or powering off the I M57.

As it draws only 28µA max from its supply, it has very low selfheating, about 0.02°C in still air.

### **Applications**

- Cell phones
- -Wireless transceivers
- -**Digital cameras**
- Personal digital assistants (PDA's)
- Battery management
- Automotive
- Disk drives
- Games
- . Appliances

### Features

- Trip temperature set by external resistors
- . External resistor tolerance contributes zero error
- Push-pull and open-drain temperature switch outputs -
- Wide operating temperature and trip-temperature range of -50°C to 150°C
- Very linear analog  $V_{\text{TEMP}}$  temperature sensor output
- Analog and digital outputs are short-circuit protected
- -TRIP-TEST pin allows in-system testing
- Latching function for the digital outputs
- Very small 2.5 mm by 2.5 mm 8-Pin LLP package

### **Key Specifications**

- Supply voltage 2.4V to 5.5V Supply current 24 µA (typ) Temperature switch accuracy -
- Analog (V<sub>TEMP</sub>) Accuracy ±0.7°C -50°C to 150°C Operating temperature Hysteresis magnitude 5°C, 10°C

**Connection Diagram** 



# **Typical Application**



FIGURE 1. Over-Temperature Output to Microcontroller **Digital Input** 

±1.5°C



Pin D	escrip	tions		
Pin No.	Name	Туре	Equivalent Circuit	Description
1	GND	Ground		Power Supply Ground
2	R <sub>SENSE1</sub>			Trip-Point Resistor Sense. One of two sense pins which selects the temperature at which $T_{OVER}$ and $\overline{T_{OVER}}$ will go active.
3	R <sub>SENSE2</sub>			Trip-Point Resistor Sense. One of two sense pins which selects the temperature at which $T_{OVER}$ and $\overline{T_{OVER}}$ will go active.
4	V <sub>DD</sub>	Power		Supply Voltage
5	TRIP TEST	Digital Input	VDD VDD VDD VDD VDD VDD VDD VDD VDD VDD	TRIP TEST pin. Active High input.If TRIP TEST = 0 (Default), then the $V_{TEMP}$ output has the analogtemperature sensor output voltage.If TRIP TEST = 1, then $T_{OVER}$ and $\overline{T_{OVER}}$ outputs are asserted and $V_{TEMP} = V_{TRIP}$ , the Temperature Trip Voltage.Tie this pin to ground if not used.
6	T <sub>OVER</sub>	Digital Output		Over Temperature Switch output Active High, Push-Pull Asserted when the measured temperature exceeds the Trip Point Temperature or if TRIP TEST = 1 This pin may be left open if not used.
7	T <sub>over</sub>	Digital Output		Over Temperature Switch output Active Low, Open-drain (See Section 2.1 regarding required pull- up resistor.) Asserted when the measured temperature exceeds the Trip Point Temperature or if TRIP TEST = 1 This pin may be left open if not used.
8	V <sub>TEMP</sub>	Analog Output		$V_{\text{TEMP}}$ Analog Voltage Output If TRIP TEST = 0, then $V_{\text{TEMP}} = V_{\text{TS}}$ , Temperature Sensor Output Voltage If TRIP TEST = 1, then $V_{\text{TEMP}} = V_{\text{TRIP}}$ , Temperature Trip Voltage This pin may be left open if not used.

# **Ordering Information**

Package	Part Number	Package Marking	Transport Media	NSC Drawing
	LM57BISD-5	57B5	1k Units Tape and Reel	SDA08B
	LM57BISDX-5	57B5	4.5k Units Tape and Reel	SDA08B
	LM57BISD-10	57B9	1k Units Tape and Reel	SDA08B
	LM57BISDX-10	57B9	4.5k Units Tape and Reel	SDA08B
0-PIII LLP	LM57CISD-5	57C5	1k Units Tape and Reel	SDA08B
	LM57CISDX-5	57C5	4.5k Units Tape and Reel	SDA08B
	LM57CISD-10	57C9	1k Units Tape and Reel	SDA08B
	LM57CISDX-10	57C9	4.5k Units Tape and Reel	SDA08B

### Note:

The "-5" suffix is for 5°C hysteresis

The "-10" suffix is for 10°C hysteresis

Contact National Semiconductor Corporation for high temperature die (above 150°C).

### Absolute Maximum Ratings (Note 1)

		Charged Device Model	1250
Supply Voltage	–0.3V to 6V	Soldering process must comply with Nati	onal's Reflow
Voltage at T <sub>OVER</sub>	–0.3V to 6V	Temperature Profile specifications. Refer	to www.national.com/
Voltage at T <sub>OVEB</sub> , V <sub>TEMP</sub> , TRIP-TEST,		packaging. (Note 3)	
R <sub>SENSE1</sub> , and R <sub>SENSE2</sub>	–0.3V to (V <sub>DD</sub> + 0.3V)	Operating Datings	
Current at any pin	5 mA	Operating Ratings (Note	1)
Storage Temperature Range	–65°C to 150°C	Specified Temperature Range	–50°C to 150°C
ESD Susceptibility (Note 2)		Supply Voltage Range	+2.4 V to 5.5V
Human Body Model	5500V		

Machine Model

450V

Accuracy Characteristics There are four gains corresponding to each of the four Temperature Trip Point Ranges.

J2 is the sensor gain used for Temperature Trip Point -41°C to 51.8°C.

J3 is for Trip Points 52°C to 97°C.

J4 for 97°C to 119°C.

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J5 for 119°C to 150°C.

### **Trip Point Accuracy**

Parameter		Conditio	n	LM57B	LM57C	Units (M ax)
	J2	$T_A = -41^{\circ}C$ to 52°C	V <sub>DD</sub> = 2.4V to 5.5V	±1.5	±2.3	°C
Trip Point Accuracy	J3	$T_A = 52^{\circ}C \text{ to } 97^{\circ}C$	V <sub>DD</sub> = 2.4V to 5.5V	±1.5	±2.3	°C
tolerance) (Note 9)	J4	T <sub>A</sub> = 97°C to 119°C	V <sub>DD</sub> = 2.4V to 5.5V	±1.5	±2.3	°C
	J5	T <sub>A</sub> = 119°C to 150°C	$V_{DD} = 2.4V$ to 5.5V	±1.5	±2.3	°C

V<sub>TEMP</sub> Analog Temperature Sensor Output Accuracy These limits do not include DC load regulation. These stated accuracy limits are with reference to the values in the LM57 V<sub>TEMP</sub> Temperature-to-Voltage Table.

Parameter		Condition			LM57C	Units (Max)	
	J2	$T_A = -50^{\circ}C$ to $150^{\circ}C$	$V_{DD} = 2.4 V \text{ to } 5.5 V$	±0.95	±1.3	°C	
	J3	$T_A = -50^{\circ}C$ to $150^{\circ}C$	$V_{DD} = 2.4 V \text{ to } 5.5 V$	±0.8	±1.3	°C	
V <sub>TEMP</sub> Accuracy (These stated accuracy limits are	J4	$T_A = 20^{\circ}C \text{ to } 50^{\circ}C$	$V_{DD} = 2.4 V \text{ to } 5.5 V$	±0.7	±1.3	°C	
		$T_A = 0^{\circ}C \text{ to } 150^{\circ}C$	V <sub>DD</sub> = 2.7V to 5.5V	±0.7	±1.3		
with reference to the values in the		$T_A = -50^{\circ}C$ to $0^{\circ}C$	V <sub>DD</sub> = 3.1V to 5.5V	±0.8	±1.3		
LM57 Temperature-to-Voltage		$T_A = 60^{\circ}C \text{ to } 150^{\circ}C$	$V_{DD} = 2.4$ V to 5.5V	±0.7	±1.3		
Table) (Note 9)	15	$T_A = 20^{\circ}C \text{ to } 50^{\circ}C$	$V_{DD} = 2.9V \text{ to } 5.5V$	±0.7	±1.3	°C	
	15	$T_A = 0^{\circ}C \text{ to } 150^{\circ}C$	V <sub>DD</sub> = 3.2V to 5.5V	±0.7	±1.3		
		$T_A = -50^{\circ}C$ to $0^{\circ}C$	$V_{DD} = 4.0V \text{ to } 5.5V$	±0.8	±1.3		

### **Electrical Characteristics**

Unless otherwise noted, these specifications apply for  $V_{DD}$  = 2.4V to 5.5V. **Boldface** limits apply for  $T_A = T_J = T_{MIN}$  to  $T_{MAX}$ ; All other limits apply to  $T_A = T_J = +25^{\circ}C$ , unless otherwise noted.

Symbol	Parameter	Conditions	Min (Note 5)	Typ (Note 4)	Max (Note 5)	Units
Tempera	ture Sensor					
		J2 –41°C to 52°C		-5.166		
	V Songer Gain	J3 52°C to 97°C		-7.752		m\//ºC
	V <sub>TEMP</sub> Sensor Gain	J4 97°C to 119°C		-10.339		mv/ C
		J5 119°C to 150°C		-12.924		
	Line Regulation DC: Supply to	$V_{\rm c} = 2.4V$ to 5.5V. Gain = 14		0.18		mV
	V <sub>TEND</sub> (Note 6)	$v_{DD} = 2.4$ v to 5.5 v, Gain = 54, Temp - 90°C		58		μV/V
				-84		dB
		Source $\leq$ 240 µA, (V <sub>DD</sub> - V <sub>TEMP</sub> ) $\geq$ 200 mV			-1	
	Load Regulation: V <sub>TEMP</sub> Output	Sink ≤ 300 µA, V <sub>TEMP</sub> ≥ 360 mV			1	mv
		Source or Sink = 100 µA		1		Ω
	Load Capacitance: V <sub>TEMP</sub> Output (Note 11)	No output series resistor required (See section 5.2)			1100	pF
I <sub>S</sub>	Supply Current: Quiescent (Note 7)			24	28	μA
TRIP-TES	ST Input				•	
V <sub>IH</sub>	Logic "1" Threshold Voltage		V <sub>DD</sub> - 0.5			V
V <sub>IL</sub>	Logic "0" Threshold Voltage				0.5	V
I	Logic "1" Input Current			1.4	3	μA
I	Logic "0" Input Leakage Current (Note 8)			0.001	1	μA
T <sub>OVEB</sub> (Pu	ush-Pull, Active-High) Output				Į	
		Source ≤ 600 µA	V <sub>DD</sub> - 0.2			
V <sub>OH</sub>	Logic "1" Push-Pull Output Voltage	Source ≤ 1.2 mA	V <sub>DD</sub> - 0.45			V
		Sink ≤ 600 μA			0.2	
V <sub>OL</sub>	Logic "0" Output Voltage	Sink ≤ 1.2 mA			0.45	V
T <sub>OVER</sub> (O	pen-Drain, Active-Low) Output					
		Sink ≤ 600 μA			0.2	
V <sub>OL</sub>	Logic "0" Output Voltage	Sink ≤1.2 mA			0.45	V
I <sub>ОН</sub>	Logic "1" Output Leakage Current (Note 8)	Temperature = 30°C		0.001	1	μA
Hysteres	is					
т	Hystoresis Temperature	5°C hysteresis option	4.7	5	5.4	°C
'HYST		10°C hysteresis option	9.6	10	10.6	°C
Timing						
t <sub>EN</sub>	Time from power on to Digital Output Enabled (Note 11)			1.0	2.9	ms
t <sub>VTEMP</sub>	Time from Power on to Analog Temperature (V <sub>TEMP</sub> ) valid (Note 11)			1.0	2.9	ms

Note 1: Absolute Maximum Ratings indicate limits beyond which damage may occur. Operating Ratings indicate conditions for which the device is intended to be functional, but specific performance is not guaranteed. For guaranteed specifications and test conditions, see the Electrical Characteristics.

Note 2: The Human Body Model (HBM) is a 100 pF capacitor charged to the specified voltage then discharged through a 1.5 kΩ resistor into each pin. The Machine Model (MM) is a 200 pF capacitor charged to the specified voltage then discharged directly into each pin. The Charged Device Model (CDM) is a specified circuit characterizing an ESD event that occurs when a device acquires charge through some triboelectric (frictional) or electrostatic induction processes and then abruptly touches a grounded object or surface.

Note 3: Reflow temperature profiles are different for lead-free and non-lead-free packages.

**Note 4:** Typicals are at  $T_J = T_A = 25^{\circ}C$  and represent most likely parametric norm.

Note 5: Limits are guaranteed to National's AOQL (Average Outgoing Quality Level).

Note 6: Line regulation (DC) is calculated by subtracting the output voltage at the highest supply voltage from the output voltage at the lowest supply voltage. The typical DC line regulation specification does not include the output voltage shift discussed in Section 5.3.

Note 7: Supply Current refers to the quiescent current of the LM57 only and does not include any load current

Note 8: This current is leakage current only and is therefore highest at high temperatures. Prototype test indicate that the leakage is well below 1  $\mu$ A over the full temperature range. This 1  $\mu$ A specification reflects the limitations of measuring leakage at room temperature. For this reason only, the leakage current is not guaranteed at a lower value.

Note 9: Accuracy is defined as the error between the measured and reference output voltages, tabulated in the Conversion Table at the specified conditions of supply gain setting, voltage, and temperature (expressed in °C). Accuracy limits include line regulation within the specified conditions. Accuracy limits do not include load regulation; they assume no DC load.

Note 10: Source currents are flowing out of the LM57. Sink currents are flowing into the LM57. Load Regulation is calculated by measuring Vtemp at 0 µA and subtracting the value with the conditions specified.

Note 11: Guaranteed by design and characterization.

# Definitions of $t_{EN}$ and $t_{V_{TEMP}}$





### **Typical Performance Characteristics**



### Supply Current vs. Supply Voltage

#### Supply Current vs. Temperature



www.national.com



Line Regulation: V<sub>TEMP</sub> vs. Supply Voltage











# **Application Information**

1.0 RESISTOR PROGRAMMING

### **Trip Point (°C) vs. Set-Resistor Values (**Ω**)**

	R <sub>SENSE2</sub>													
			J	2			J3 J4		4	J5				
	_	976k	825k	698k	590k	499k	412k	340k	280k	226k	178k	140k	105k	75k
	976k	-40.7	-16.3	7.3	30.4	52.7	67.8	82.7	97.5	108.6	119.6	128.5	137.3	146.1
	825k	-39.1	-14.8	8.8	31.8	53.7	68.7	83.7	98.2	109.3	120.2	129.0	137.8	146.6
	698k	-37.6	-13.3	10.2	33.2	54.6	69.6	84.6	98.9	110.0	120.7	129.6	138.4	147.2
	590k	-36.0	-11.8	11.7	34.7	55.6	70.6	85.5	99.6	110.7	121.3	130.1	138.9	147.7
	499k	-34.5	-10.3	13.1	36.1	56.5	71.5	86.5	100.3	111.4	121.8	130.7	139.5	148.3
	412k	-32.9	-8.8	14.6	37.5	57.4	72.5	87.4	100.9	112.1	122.4	131.2	140.0	148.8
	340k	-31.4	-7.3	16.1	39.0	58.4	73.4	88.3	101.6	112.8	122.9	131.8	140.6	149.3
Б	280k	-29.9	-5.8	17.5	40.4	59.3	74.3	89.3	102.3	113.5	123.5	132.3	141.1	149.9
DSENSE1	226k	-28.3	-4.3	18.9	41.8	60.3	75.3	90.2	103.0	114.2	124.0	132.9	141.7	
	178k	-26.8	-2.9	20.4	43.2	61.2	76.2	91.1	103.7	114.9	124.6	133.4	142.2	
	140k	-25.3	-1.4	21.8	44.7	62.1	77.1	92.1	104.4	115.6	125.2	134.0	142.8	
	105k	-23.8	0.0	23.2	46.1	63.1	78.1	93.0	105.1	116.3	125.7	134.5	143.3	
	75k	-22.3	1.5	24.7	47.5	64.0	79.0	93.9	105.8	117.0	126.3	135.1	143.9	
	46.4k	-20.8	3.0	26.1	48.9	65.0	79.9	94.8	106.5	117.6	126.8	135.6	144.4	
	22.6k	-19.3	4.4	27.5	50.3	65.9	80.9	95.8	107.2	118.3	127.4	136.2	145.0	
	0.01k	-17.8	5.9	28.9	51.8	66.8	81.8	96.7	107.9	119.0	127.9	136.7	145.5	

# $V_{\text{TEMP}}$ (mV) at the Trip Point vs. Set-Resistor Value ( $\Omega)$

	R <sub>SENSE2</sub>													
		J2			J3		J4		J5					
		976k	825k	698k	590k	499k	412k	340k	280k	226k	178k	140k	105k	75k
	976k	1306.2	1183.8	1064.0	945.6	1243.7	1125.3	1006.8	1185.3	1066.0	1184.0	1064.6	944.8	825.0
	825k	1298.5	1176.2	1056.6	938.2	1236.3	1117.9	999.3	1177.8	1058.5	1176.6	1057.1	937.3	817.5
	698k	1290.7	1168.7	1049.1	930.8	1228.9	1110.5	991.9	1170.4	1051.0	1169.1	1049.6	929.8	810.1
	590k	1283.0	1161.2	1041.7	923.4	1221.5	1103.1	984.5	1163.0	1043.6	1161.6	1042.1	922.3	802.7
	499k	1275.3	1153.6	1034.3	916.0	1214.1	1095.7	977.1	1155.5	1036.1	1154.2	1034.6	914.8	795.2
	412k	1267.6	1146.1	1026.8	908.6	1206.7	1088.3	969.7	1148.1	1028.6	1146.7	1027.2	907.3	787.8
	340k	1259.9	1138.6	1019.4	901.2	1199.3	1080.9	962.2	1140.7	1021.1	1139.2	1019.7	899.8	780.3
Б	280k	1252.2	1131.0	1012.0	893.8	1191.9	1073.5	954.8	1133.2	1013.6	1131.7	1012.2	892.3	772.9
DSENSE1	226k	1244.6	1123.5	1004.6	886.4	1184.5	1066.0	947.3	1125.8	1006.1	1124.3	1004.7	884.8	
	178k	1237.0	1116.0	997.3	879.0	1177.1	1058.6	939.9	1118.3	998.7	1116.8	997.2	877.3	
	140k	1229.4	1108.6	989.9	871.6	1169.7	1051.2	932.5	1110.9	991.2	1109.3	989.7	869.8	
	105k	1221.8	1101.2	982.5	864.2	1162.3	1043.8	925.0	1103.5	983.7	1101.8	982.2	862.3	
	75k	1214.1	1093.7	975.2	856.8	1154.9	1036.4	917.6	1096.0	976.2	1094.4	974.8	854.8	
	46.4k	1206.5	1086.3	967.8	849.4	1147.5	1029.0	910.2	1088.6	968.7	1086.9	967.3	847.3	
	22.6k	1198.9	1078.9	960.4	842.0	1140.1	1021.6	902.7	1081.2	961.2	1079.4	959.8	839.8	
	0.01k	1191.3	1071.4	953.1	834.6	1132.7	1014.2	895.3	1073.7	953.8	1072.0	952.3	832.3	

# **1.1 Selection of R<sub>SET</sub> Resistors** To set the trip point:

(1) Locate the desired trip temperature on the Trip Point Table.

(2) Identify the corresponding  $R_{SENSE2}$  value by following the column up to the resistor value.

(3) Identify the corresponding  $\rm R_{\rm SENSE1}$  value by following the row leftwards to the resistor value.

(4) Use only the standard resistor values from the list.

(5) Use only the resistor with 1% tolerance and a temperature coefficient of 100ppm (or better). These restrictions are nec-

		V <sub>TEMP</sub>	, (mV)	-
Temperature (°C)	J2	J3	J4	J5
-50	1353	2029	2705	3381
-49	1348	2021	2695	3369
-48	1343	2014	2685	3357
-47	1338	2006	2675	3344
-46	1333	1999	2665	3332
-45	1328	1992	2655	3319
-44	1323	1984	2646	3307
-43	1318	1977	2636	3294
-42	1313	1969	2626	3282
-41	1308	1962	2616	3269
-40	1303	1954	2606	3257
-39	1298	1947	2596	3244
-38	1293	1939	2586	3232
-37	1288	1932	2576	3219
-36	1283	1924	2566	3207
-35	1278	1917	2556	3194
-34	1273	1909	2546	3182
-33	1268	1902	2536	3169
-32	1263	1894	2526	3157
-31	1258	1887	2516	3144
-30	1253	1879	2506	3132
-29	1248	1872	2495	3119
-28	1243	1864	2485	3107
-27	1238	1857	2475	3094
-26	1233	1849	2465	3082
-25	1228	1841	2455	3069
-24	1223	1834	2445	3056
-23	1218	1826	2435	3044
-22	1213	1819	2425	3031
-21	1208	1811	2415	3019
-20	1203	1804	2405	3006
_19	1198	1796	2395	2993
-18	1193	1789	2385	2981
-17	1188	1781	2375	2968
-16	1182	1773	2365	2956
–15	1177	1766	2354	2943
-14	1172	1758	2344	2930
–13	1167	1751	2334	2918

### 2.0 LM57 V<sub>TEMP</sub> TEMPERATURE-TO-VOLTAGE TABLE

essary to stay at the selected setting, and not to slip into an adjacent setting.

(6) This is consistent with using resistors from the Thick Film Chip Resistors CRCW0402 family. These are available with very small dimensions of L = 1.0mm, W = 0.5mm, H =0.35mm.

(7) Note that the resistor tolerance does not diminish the accuracy of the trip point. See patent #6, 924, 758.

	V <sub>TEMP</sub> (mV)							
Temperature (°C)	J2	J3	J4	J5				
-12	1162	1743	2324	2905				
-11	1157	1735	2314	2892				
-10	1152	1728	2304	2880				
-9	1147	1720	2294	2867				
-8	1142	1713	2284	2854				
-7	1137	1705	2273	2842				
-6	1132	1697	2263	2829				
-5	1127	1690	2253	2816				
-4	1122	1682	2243	2803				
-3	1117	1675	2233	2791				
-2	1112	1667	2223	2778				
-1	1106	1659	2212	2765				
0	1101	1652	2202	2753				
1	1096	1644	2192	2740				
2	1091	1636	2182	2727				
3	1086	1629	2172	2714				
4	1081	1621	2161	2702				
5	1076	1613	2151	2689				
6	1071	1606	2141	2676				
7	1066	1598	2131	2663				
8	1061	1590	2121	2650				
9	1055	1583	2110	2638				
10	1050	1575	2100	2625				
11	1045	1567	2090	2612				
12	1040	1560	2080	2599				
13	1035	1552	2069	2586				
14	1030	1544	2059	2574				
15	1025	1537	2049	2561				
16	1020	1529	2039	2548				
17	1015	1521	2028	2535				
18	1009	1514	2018	2522				
19	1004	1506	2008	2509				
20	999	1498	1997	2497				
21	994	1490	1987	2484				
22	989	1483	1977	2471				
23	984	1475	1967	2458				
24	979	1467	1956	2445				
25	973	1460	1946	2432				

	V <sub>TEMP</sub> (mV)								
Temperature (°C)	J2	J3	J4	J5					
26	968	1452	1936	2419					
27	963	1444	1925	2406					
28	958	1436	1915	2394					
29	953	1429	1905	2381					
30	948	1421	1894	2368					
31	942	1413	1884	2355					
32	937	1405	1874	2342					
33	932	1398	1863	2329					
34	927	1390	1853	2316					
35	922	1382	1843	2303.0					
36	917	1374	1832	2290					
37	911	1367	1822	2277					
38	906	1359	1811	2264					
39	901	1351	1801	2251					
40	896	1343	1791	2238					
41	891	1335	1780	2225					
42	885	1328	1770	2212					
43	880	1320	1759	2199					
44	875	1312	1749	2186					
45	870	1304	1739	2173					
46	865	1296	1728	2160					
47	859	1289	1718	2147					
48	854	1281	1707	2134					
49	849	1273	1697	2121					
50	844	1265	1687	2108					
51	839	1257	1676	2095					
52	833	1249	1666	2082					
53	828	1242	1655	2069					
54	823	1234	1645	2056					
55	818	1226	1634	2043					
56	812	1218	1624	2030					
57	807	1210	1613	2016					
58	802	1202	1603	2003					
59	797	1194	1592	1990					
60	791	1187	1582	1977					
61	786	1179	1571	1964					
62	781	1171	1561	1951					
63	776	1163	1550	1938					
64	770	1155	1540	1925					
65	765	1147	1529	1911					
66	760	1139	1519	1898					
67	755	1131	1508	1885					
68	749	1124	1498	1872					
69	744	1116	1487	1859					
70	739	1108	1477	1846					
71	734	1100	1466	1833					
72	728	1092	1456	1819					
73	723	1084	1445	1806					

	V <sub>TEMP</sub> (mV)							
Temperature (°C)	J2	J3	J4	J5				
74	718	1076	1435	1793				
75	713	1068	1424	1780				
76	707	1060	1413	1767				
77	702	1052	1403	1753				
78	697	1044	1392	1740				
79	691	1036	1382	1727				
80	686	1028	1371	1714				
81	681	1021	1360	1700				
82	675	1013	1350	1687				
83	670	1005	1339	1674				
84	665	997	1329	1661				
85	660	989	1318	1647				
86	654	981	1307	1634				
87	649	973	1297	1621				
88	644	965	1286	1607				
89	638	957	1276	1594				
90	633	949	1265	1581				
91	628	941	1254	1568				
92	622	933	1244	1554				
93	617	925	1233	1541				
94	612	917	1222	1528				
95	606	909	1212	1514				
96	601	901	1201	1501				
97	596	893	1190	1488				
98	590	885	1180	1474				
99	585	877	1169	1461				
100	580	869	1158	1448				
101	574	861	1148	1434				
102	569	853	1137	1421				
103	564	845	1126	1407				
104	558	837	1115	1394				
105	553	829	1105	1381				
106	548	821	1094	1367				
107	542	813	1083	1354				
108	537	805	1073	1340				
109	531	797	1062	1327				
110	526	788	1051	1314				
111	521	780	1040	1300				
112	515	772	1030	1287				
113	510	764	1010	1273				
114	505	756	1008	1260				
115	<u>4</u> 99	748	997	1246				
116	404	740	986	1233				
117	488 488	732	976	1210				
118	483	794	965	1206				
110	478	716	950	1102				
120	470	702	0/2	1170				
101	4/2	700	022	1165				
121	407	1 100	900	1105				

	V <sub>TEMP</sub> (mV)			
Temperature (°C)	J2	J3	J4	J5
122	461	692	922	1152
123	456	683	911	1138
124	451	675	900	1125
125	445	667	889	1111
126	440	659	878	1098
127	434	651	868	1084
128	429	643	857	1071
129	424	635	846	1057
130	418	627	835	1044
131	413	618	824	1030
132	407	610	813	1017
133	402	602	803	1003
134	396	594	792	989
135	391	586	781	976
136	386	578	770	962
137	380	570	759	949

	V <sub>TEMP</sub> (mV)			
Temperature (°C)	J2	J3	J4	J5
138	375	561	748	935
139	369	553	737	921
140	364	545	726	908
141	358	537	716	894
142	353	529	705	881
143	347	520	694	867
144	342	512	683	853
145	336	504	672	840
146	331	496	661	826
147	326	488	650	812
148	320	480	639	799
149	315	471	628	785
150	309	463	617	771

Note: The Rset resistors select a trip point and a corresponding Vtemp gain (J2, J3, J4, or J5). The trip point range associated with a given gain is shown in bold on this table. The Vtemp gain is selected by the Rset resistors. Vtemp is valid over the entire temperature range.

### 2.1 LM57 V<sub>TEMP</sub> Voltage -To-Temperature Equations

Trip-Point Region	LM57 Trip Point Range	V <sub>TEMP</sub> (mV) Equations T(°C)
J2	-41°C to 52°C	$V_{\text{TEMP}} = 947.6 - 5.166(\text{T}-30) - 0.00129(\text{T}-30)^2$
J3	52°C to 97°C	V <sub>TEMP</sub> = 1420.9 - 7.752(T-30) - 0.00191(T-30) <sup>2</sup>
J4	97°C to 119°C	V <sub>TEMP</sub> = 1894.3 – 10.339(T-30) - 0.00253(T-30) <sup>2</sup>
J5	119°C to 150°C	V <sub>TEMP</sub> = 2367.7 -12.924(T-30) - 0.00316(T-30) <sup>2</sup>

LM57

### 3.0 T<sub>OVER</sub> AND T<sub>OVER</sub> DIGITAL OUTPUTS

The T<sub>OVER</sub> Active High, Push-Pull Output and the  $\overline{T_{OVER}}$  Active Low, Open-Drain Output both assert at the same time whenever the Die Temperature reaches the Trip Point. They also assert simultaneously whenever the TRIP TEST pin is set high. Both outputs de-assert when the die temperature goes below the (Temperature Trip Point) - (Hysteresis). These two types of digital outputs enable the user the flexibility to choose the type of output that is most suitable for his design.

Either the  $T_{\rm OVER}$  or the  $\overline{T_{\rm OVER}}$  Digital Output pins can be left open if not used.

The  $\overline{T_{OVER}}$  Active Low, Open-Drain Digital Output, if used, requires a pull-up resistor between this pin and V<sub>DD</sub>.

#### 3.1T<sub>OVER</sub> and $\overline{T_{OVER}}$ Noise Immunity

The LM57 has some noise immunity to a premature trigger due to noise on the power supply. With the die temperature at 1°C below the trip point, there are no premature triggers for a square wave injected into the power supply with a magnitude of 100 mV<sub>PP</sub> over a frequency range of 100 Hz to 2 MHz. Above the frequency a premature trigger may occur.

With the die temperature at 2°C below the trip point, and a magnitude of 200 mV<sub>PP</sub>, there are no premature triggers from 100 Hz to 300 kHz. Above that frequency a premature trigger may occur.

Therefore if the supply line is noisy, it is recommended that a local supply decoupling cap be used to reduce that noise.

### **4.0 TRIP TEST DIGITAL INPUT**

The TRIP TEST pin provides a means to test the digital outputs by causing them to assert, regardless of temperature.

In addition, when the TRIP TEST pin is pulled high the  $V_{\text{TEMP}}$  pin will be at the  $V_{\text{TRIP}}$  voltage.

### 5.0 V<sub>TEMP</sub> ANALOG TEMPERATURE SENSOR OUTPUT

The V<sub>TEMP</sub> push-pull output provides the ability to sink and source significant current. This is beneficial when, for example, driving dynamic loads like an input stage on an analog-to-digital converter (ADC). In these applications the source current is required to quickly charge the input capacitor of the ADC. See the Applications Circuits section for more discussion of this topic. The LM57 is ideal for this and other applications which require strong source or sink current.

### 5.1 V<sub>TEMP</sub> Noise Considerations

A load capacitor on  $V_{\text{TEMP}}$  can help to filter noise.

For noisy environments, a 100nF supply decoupling cap placed closed across  $\rm V_{\rm DD}$  and GND pins of LM57 is recommended.

#### 5.2 V<sub>TEMP</sub> Capacitive Loads

The V<sub>TEMP</sub> Output handles capacitive loading well. In an extremely noisy environment, or when driving a switched sampling input on an ADC, it may be necessary to add some filtering to minimize noise coupling. Without any precautions, the V<sub>TEMP</sub> can drive a capacitive load less than or equal to 1100 pF as shown in *Figure 2*. For capacitive loads greater than 1100 pF, a series resistor is required on the output, as shown in *Figure 3*, to maintain stable conditions.



FIGURE 2. LM57 No Isolation Resistor Required



CLOAD	Minimum R <sub>S</sub>
1.1 nF to 99 nF	3 kΩ
100 nF to 999 nF	1.5 kΩ
1 µF	750 Ω

#### FIGURE 3. LM57 with Series Resistor for Capacitive Loading greater than 1100 pF.

#### 5.3 V<sub>TEMP</sub> Voltage Shift

The LM57 is very linear over temperature and supply voltage range. Due to the intrinsic behavior of an NMOS/PMOS rail-to-rail buffer, a slight shift in the output can occur when the supply voltage is ramped over the operating range of the device. The location of the shift is determined by the relative levels of V<sub>DD</sub> and V<sub>TEMP</sub>. The shift typically occurs when V<sub>DD</sub> - V<sub>TEMP</sub> = 1.0V.

This slight shift (a few millivolts) takes place over a wide change (approximately 200 mV) in V<sub>DD</sub> or V<sub>TEMP</sub>. Since the shift takes place over a wide temperature change of 5°C to 20°C, V<sub>TEMP</sub> is always monotonic. The accuracy specifications in the Electrical Characteristics table already includes this possible shift.

#### 6.0 MOUNTING AND TEMPERATURE CONDUCTIVITY

The LM57 can be applied easily in the same way as other integrated-circuit temperature sensors. It can be glued or cemented to a surface.

To ensure good temperature conductivity, the backside of the LM57 die is directly attached to the exposed pad. The temperatures of the lands and traces to the other leads of the LM57 will also affect the temperature reading.

Alternatively, the LM57 can be mounted inside a sealed-end metal tube, and can then be dipped into a bath or screwed into a threaded hole in a tank. As with any IC, the LM57 and accompanying wiring and circuits must be kept insulated and dry, to avoid leakage and corrosion. This is especially true if the circuit may operate at cold temperatures where condensation can occur. If moisture creates a short circuit from the

 $V_{\text{TEMP}}$  output to ground or  $V_{\text{DD}},$  the  $V_{\text{TEMP}}$  output from the LM57 will not be correct. Printed-circuit coatings are often used to ensure that moisture cannot corrode the leads or circuit traces.

The LM57's junction temperature is the actual temperature being measured. The thermal resistance junction-to-ambient ( $\theta_{JA}$ ) is the parameter (from Figure 4) used to calculate the rise of a device junction temperature due to its power dissipation. The equation used to calculate the rise in the LM57's die temperature is

$$\mathsf{T}_{\mathsf{J}} = \mathsf{T}_{\mathsf{A}} + \theta_{\mathsf{J}\mathsf{A}} \left[ \left( \mathsf{V}_{\mathsf{D}\mathsf{D}} \mathsf{I}_{\mathsf{Q}} \right) + \left( \mathsf{V}_{\mathsf{D}\mathsf{D}} - \mathsf{V}_{\mathsf{T}\mathsf{E}\mathsf{M}\mathsf{P}} \right) \; \mathsf{I}_{\mathsf{L}} \right]$$

where  $T_A$  is the ambient temperature,  $I_Q$  is the quiescent current,  $I_L$  is the load current on Vtemp.

For example, in an application where  $T_A = 30$  °C,  $V_{DD} = 5.5$  V,  $I_{DD} = 28 \ \mu$ A, J5 gain,  $V_{TEMP} = 2368 \ m$ W, and  $I_L = 0 \ \mu$ A, the total temperature rise would be  $[152^{\circ}C/W^{+}5.5V^{+}28\mu$ A] = 0.023°C. To minimize self-heating, the load current on Vtemp should be minimized.

Device Number	Thermal Resistance (θ <sub>JA</sub> )	NS Package Number	
LM57	152° C/W	SDA08B	

### FIGURE 4. LM57 Thermal Resistance

#### 7.0 Rset TABLE

The LM57 uses the voltage at the two Rsense pins to set the trip point for the temperature switch. It is possible to drive the

two Rsense pins with a voltage equal to the value generated by the resistor and the internal current-source and have the same switch point. Thus one can use an external DAC to drive each Rsense pin, allowing for the temperature trip point to be set dynamically by the system processor. The table shows the Rset value and its corresponding generated Rsense pin voltage (the "Center Value").

Rset Values	(kO) v	s Rsense	Voltage	(mV)
nact values	(1122) V	3 11301130	Vonage	(

<b>D</b> <sub>1</sub> (0)	Rsense Voltage (mV)	
HSET (12)	Center Value	
976k	1875	
825k	1585	
698k	1341	
590k	1134	
499k	959	
412k	792	
340k	653	
280k	538	
226k	434	
178k	342	
140k	269	
105k	202	
75k	146	
46.4k	87	
22.6k	43	
0.01k	0	

# **Applications Circuits**



FIGURE 5. Temperature Switch Using Push-Pull Output



FIGURE 6. Temperature Switch Using Open-Drain Output



Most CMOS ADCs found in microcontrollers and ASICs have a sampled data comparator input structure. When the ADC charges the sampling cap, it requires instantaneous charge from the output of the analog source such as the LM57 temperature sensor and many op amps. This requirement is easily accommodated by the addition of a capacitor ( $C_{FILTER}$ ). The size of  $C_{FILTER}$  depends on the size of the sampling capacitor and the sampling frequency. Since not all ADCs have identical input stages, the charge requirements will vary. This general ADC application is shown as an example only.





FIGURE 8. TRIP TEST Digital Output Test Circuit





8-Pin LLP NS Package Number SDA08B

# Notes

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www.national.com/power	Green Compliance	www.national.com/quality/green		
www.national.com/switchers	Distributors	www.national.com/contacts		
www.national.com/ldo	Quality and Reliability	www.national.com/quality		
www.national.com/led	Feedback/Support	www.national.com/feedback		
www.national.com/vref	Design Made Easy	www.national.com/easy		
www.national.com/powerwise	Solutions	www.national.com/solutions		
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